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16 MAY 2002

218478US-227607-8011-2-PCT

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

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3-20-03

IN RE APPLICATION OF :
YASUJI HIRAMATSU ET AL. : ATTN: APPLICATION DIVISION
SERIAL NO: 10/030,123 :
FILED: JANUARY 24, 2002 :
FOR: SEMICONDUCTOR-PRODUCING/:
EXAMINING DEVICE

PRELIMINARY AMENDMENT

ASSISTANT COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

SIR:

Prior to a first examination on the merits, please amend the above-identified application as follows:

IN THE CLAIMS

Please amend Claims 3 and 4 to read as follows:¹

3. (Amended) The semiconductor-producing/examining device according to claim 1,
wherein
the connection between said conductor layer and said external terminal, or
the connection between said another conductor layer and said external terminal
is performed through a non-oxidizable metal layer.

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¹A marked-up copy of the amendments is attached hereto.